

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10714654	TAKEKOSHI ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	RANDOLPH CHU	2624

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	100, 128	6/6/2007	ric
705	2.3	6/6/2007	ric
715	716	3/20/2008	ric
707	2	3/20/2008	ric
382	305	10/23/2008	ric
358	403, 404	10/23/2008	ric

<b>SEARCH NOTES</b>			
<b>Search Notes</b>		<b>Date</b>	<b>Examiner</b>
EAST		6/6/2007	ric
Inventor Name Search		6/6/2007	ric
Consult with Wenpeng Chen		6/6/2007	ric
Updated EAST Search		12/7/2007	ric
Updated EAST Search		3/20/2008	ric
STIC Search		10/23/2008	ric
Updated EAST Search		10/23/2008	ric
Consult with Andy Johns		10/23/2008	ric

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/RANDOLPH CHU/  
Examiner.Alt Unit 2624